



Keywords: CMOS; soft X-ray FEL applications; single-shot experiment; time resolved

Single-shot experiments at the soft X-FEL FERMI using a back-side-illuminated scientific CMOS detector. Corrigendum

Cyril Léveillé,^{a*} Kewin Desjardins,^a Horia Popescu,^a Boris Vodungbo,^b Marcel Hennes,^b Renaud Delaunay,^b Emmanuelle Jal,^b Dario De Angelis,^c Matteo Pancaldi,^c Emanuele Pedersoli,^c Flavio Capotondi^c and Nicolas Jaouen^{a*}

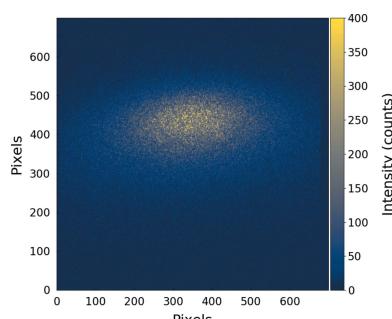
^aSynchrotron SOLEIL, L'Orme des Merisiers, Saint-Aubin, BP48, 91192 Gif-sur-Yvette, France, ^bSorbonne Université, CNRS, Laboratoire de Chimie Physique-Matière et Rayonnement, LCPMR, 75005 Paris, France, and ^cElettra-Sincrotrone Trieste, Basovizza, Trieste 34149, Italy. *Correspondence e-mail: cyril.leveille@synchrotron-soleil.fr, nicolas.jaouen@synchrotron-soleil.fr

The name of one of the authors in the article by Léveillé *et al.* [(2022), *J. Synchrotron Rad.* **29**, 103–110] is corrected.

In the article by Léveillé *et al.* (2022) the name of the fourth author was given incorrectly. The correct name is Boris Vodungbo, as given above.

References

Léveillé, C., Desjardins, K., Popescu, H., Vondungbo, B., Hennes, M., Delaunay, R., Jal, E., De Angelis, D., Pancaldi, M., Pedersoli, E., Capotondi, F. & Jaouen, N. (2022). *J. Synchrotron Rad.* **29**, 103–110.



OPEN ACCESS

Published under a CC BY 4.0 licence